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FAIRCHILD SEMICONDUCTOR®

December 2013

FCD9N60NTM

N-Channel SupreMOS® MOSFET

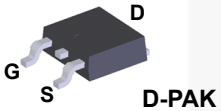
600 V, 9 A, 385 mΩ

Features

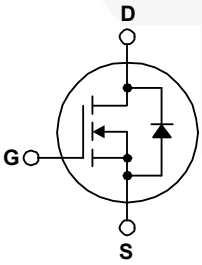
- $R_{DS(on)}$ = 330 mΩ (Typ.) @ V_{GS} = 10 V, I_D = 4.5 A
- Ultra Low Gate Charge (Typ. Q_g = 17.8 nC)
- Low Effective Output Capacitance
- 100% Avalanche Tested
- RoHS Compliant

Description

The SupreMOS® MOSFET is Fairchild Semiconductor's next generation of high voltage super-junction (SJ) technology employing a deep trench filling process that differentiates it from the conventional SJ MOSFETs. This advanced technology and precise process control provides lowest Rsp on-resistance, superior switching performance and ruggedness. SupreMOS MOSFET is suitable for high frequency switching power converter applications such as PFC, server/telecom power, FPD TV power, ATX power, and industrial power applications.



D-PAK



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter			FCD9N60NTM	Unit
V_{DSS}	Drain to Source Voltage			600	V
V_{GSS}	Gate to Source Voltage			±30	V
I_D	Drain Current	- Continuous (T_C = 25°C)		9.0	A
		- Continuous (T_C = 100°C)		5.7	
I_{DM}	Drain Current	- Pulsed	(Note 1)	27	A
E_{AS}	Single Pulsed Avalanche Energy		(Note 2)	135	mJ
I_{AR}	Avalanche Current		(Note 1)	9.0	A
E_{AR}	Repetitive Avalanche Energy		(Note 1)	9.3	mJ
dv/dt	MOSFET dv/dt Ruggedness			100	V/ns
	Peak Diode Recovery dv/dt		(Note 3)	15	
P_D	Power Dissipation	(T_C = 25°C)		92.6	W
		- Derate above 25°C		0.74	W/°C
T_J, T_{STG}	Operating and Storage Temperature Range			-55 to +150	°C
T_L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

Thermal Characteristics

Symbol	Parameter	FCD9N60NTM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.35	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCD9N60NTM	FCD9N60NTM	D-PAK	Tape and Reel	330 mm	16 mm	2500 units

Electrical Characteristics $T_C = 25^oC$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 1mA, V_{GS} = 0V, $T_J = 25^oC$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 1mA, Referenced to 25^oC	-	0.8	-	$V/^oC$
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 480V, V_{GS} = 0V	-	-	10	μA
		V_{DS} = 480V, V_{GS} = 0V, $T_C = 125^oC$	-	-	100	
I_{GSS}	Gate to Body Leakage Current	V_{GS} = ±30V, V_{DS} = 0V	-	-	±100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	V_{GS} = V_{DS}, I_D = 250μA	3.0	-	5.0	V
$R_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10V, I_D = 4.5A	-	0.330	0.385	Ω
g_{FS}	Forward Transconductance	V_{DS} = 40V, I_D = 4.5A	-	5.3	-	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 100V, V_{GS} = 0V, f = 1MHz	-	735	1000	pF
C_{oss}	Output Capacitance		-	40	53	pF
C_{rss}	Reverse Transfer Capacitance		-	3.5	5.5	pF
C_{oss}	Output Capacitance	V_{DS} = 380V, V_{GS} = 0V, f = 1MHz	-	23.7	-	pF
$C_{oss(eff.)}$	Effective Output Capacitance	V_{DS} = 0V to 380V, V_{GS} = 0V	-	122	-	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 380V, I_D = 4.5A, R_{GEN} = 4.7Ω (Note 4)	-	13.2	-	ns
t_r	Turn-On Rise Time		-	9.6	-	ns
$t_{d(off)}$	Turn-Off Delay Time		-	28.7	-	ns
t_f	Turn-Off Fall Time		-	11.5	-	ns
$Q_{g(tot)}$	Total Gate Charge at 10V	V_{DS} = 380V, I_D = 4.5A, V_{GS} = 10V (Note 4)	-	17.8	-	nC
Q_{gs}	Gate to Source Gate Charge		-	4.2	-	nC
Q_{gd}	Gate to Drain “Miller” Charge		-	7.6	-	nC
ESR	Equivalent Series Resistance(G-S)	f = 1MHz	-	2.65	-	Ω
Drain-Source Diode Characteristics						
I_S	Maximum Continuous Drain to Source Diode Forward Current		-	9.0	-	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	27	-	A
V_{SD}	Drain to Source Diode Forward Voltage	V_{GS} = 0V, I_{SD} = 9A	-	-	1.2	V
t_{rr}	Reverse Recovery Time	V_{GS} = 0V, I_{SD} = 9A, dI_F/dt = 100A/μs	-	322	-	ns
Q_{rr}	Reverse Recovery Charge		-	5.04	-	μC

Notes:

1. Repetitive rating: pulse-width limited by maximum junction temperature.
2. I_{AS} = 3 A, R_G = 25 Ω, starting $T_J = 25°C$.
3. $I_{SD} \le 9$ A, di/dt ≤ 200 A/μs, $V_{DD} \le 380$ V, starting $T_J = 25°C$.
4. Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics

Figure 1. On-Region Characteristics

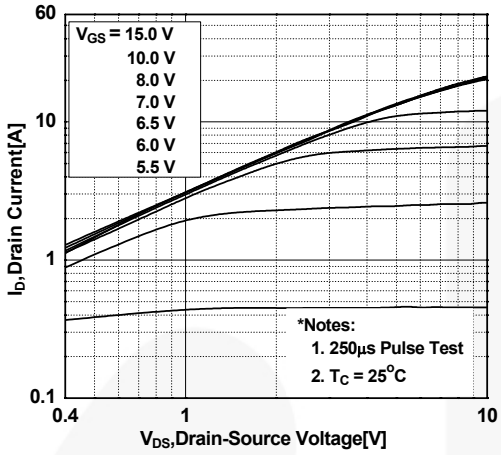


Figure 2. Transfer Characteristics

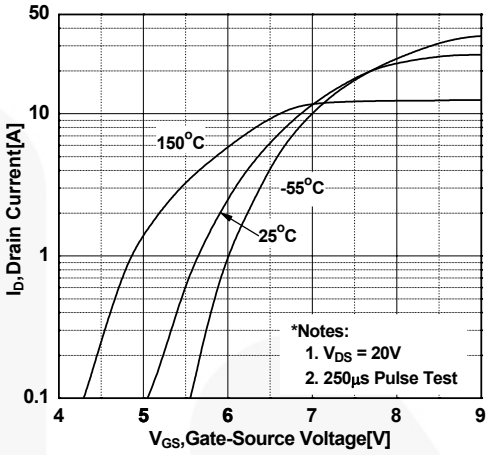


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

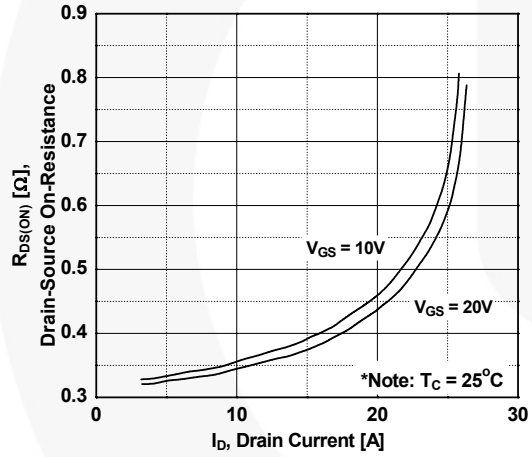


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

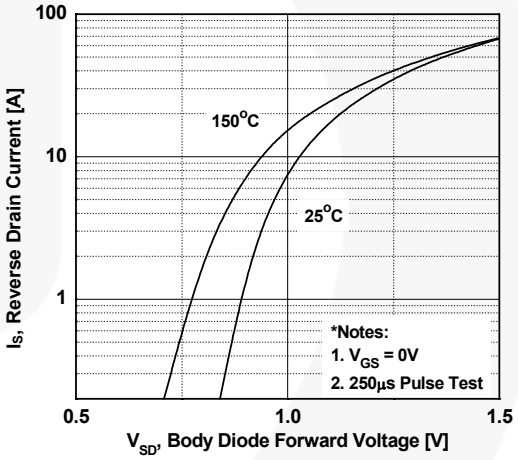


Figure 5. Capacitance Characteristics

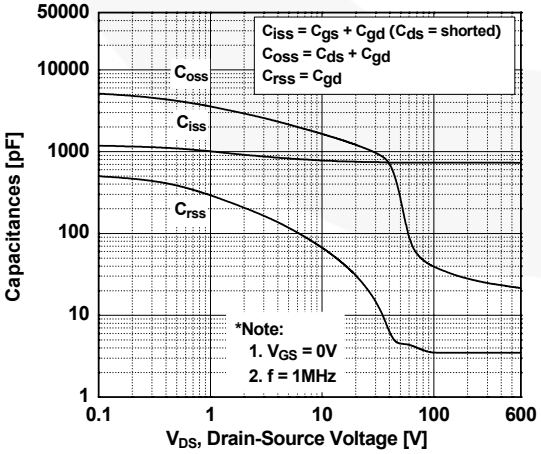
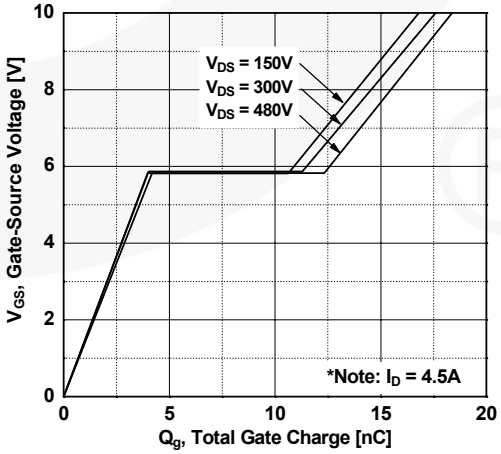


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

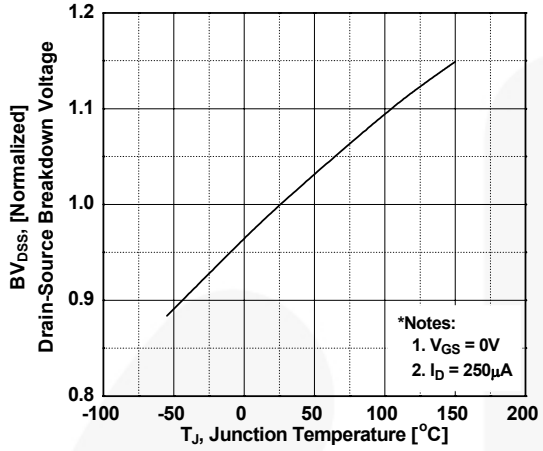


Figure 8. On-Resistance Variation vs. Temperature

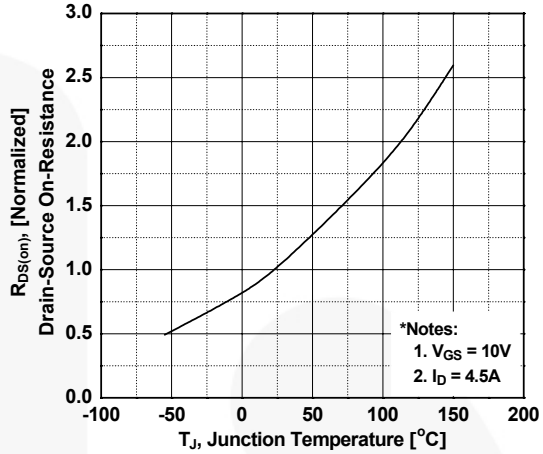


Figure 9. Maximum Safe Operating Area

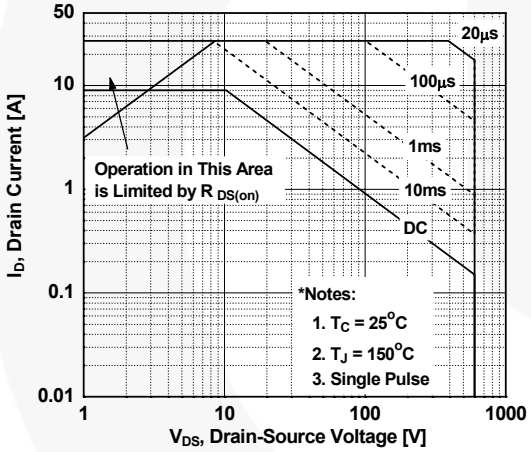


Figure 10. Maximum Drain Current vs. Case Temperature

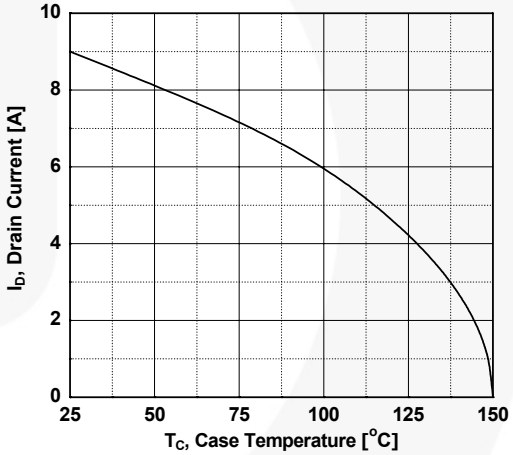
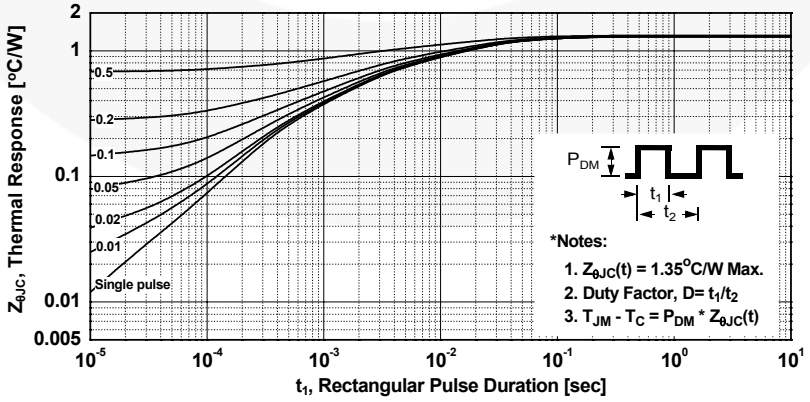


Figure 11. Transient Thermal Response Curve



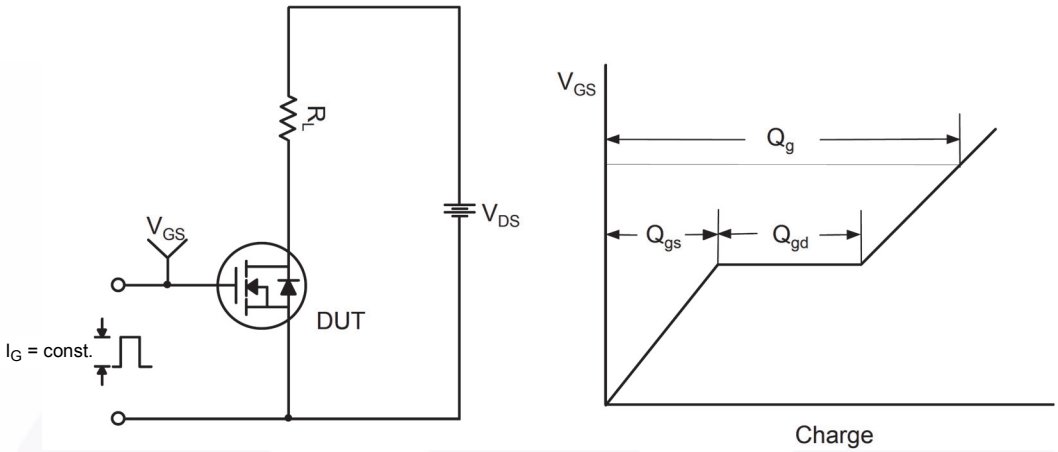


Figure 12. Gate Charge Test Circuit & Waveform

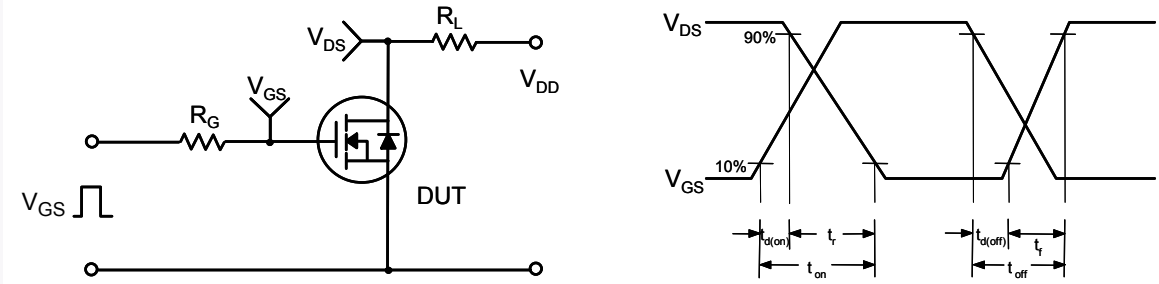


Figure 13. Resistive Switching Test Circuit & Waveforms

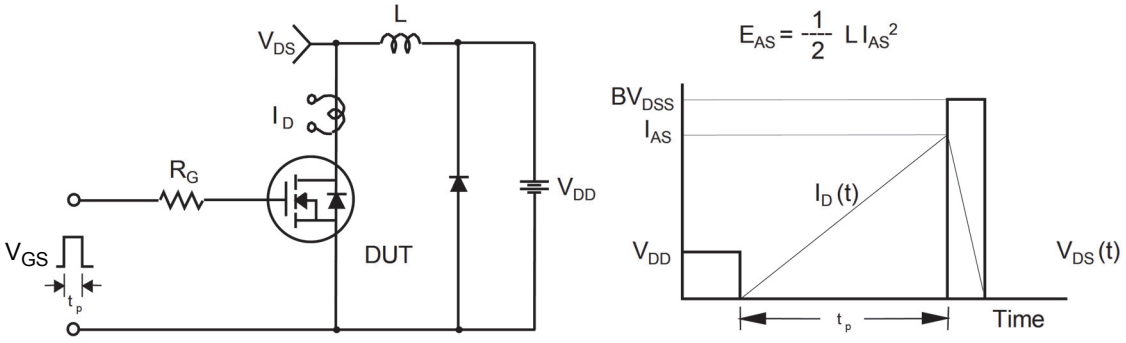


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

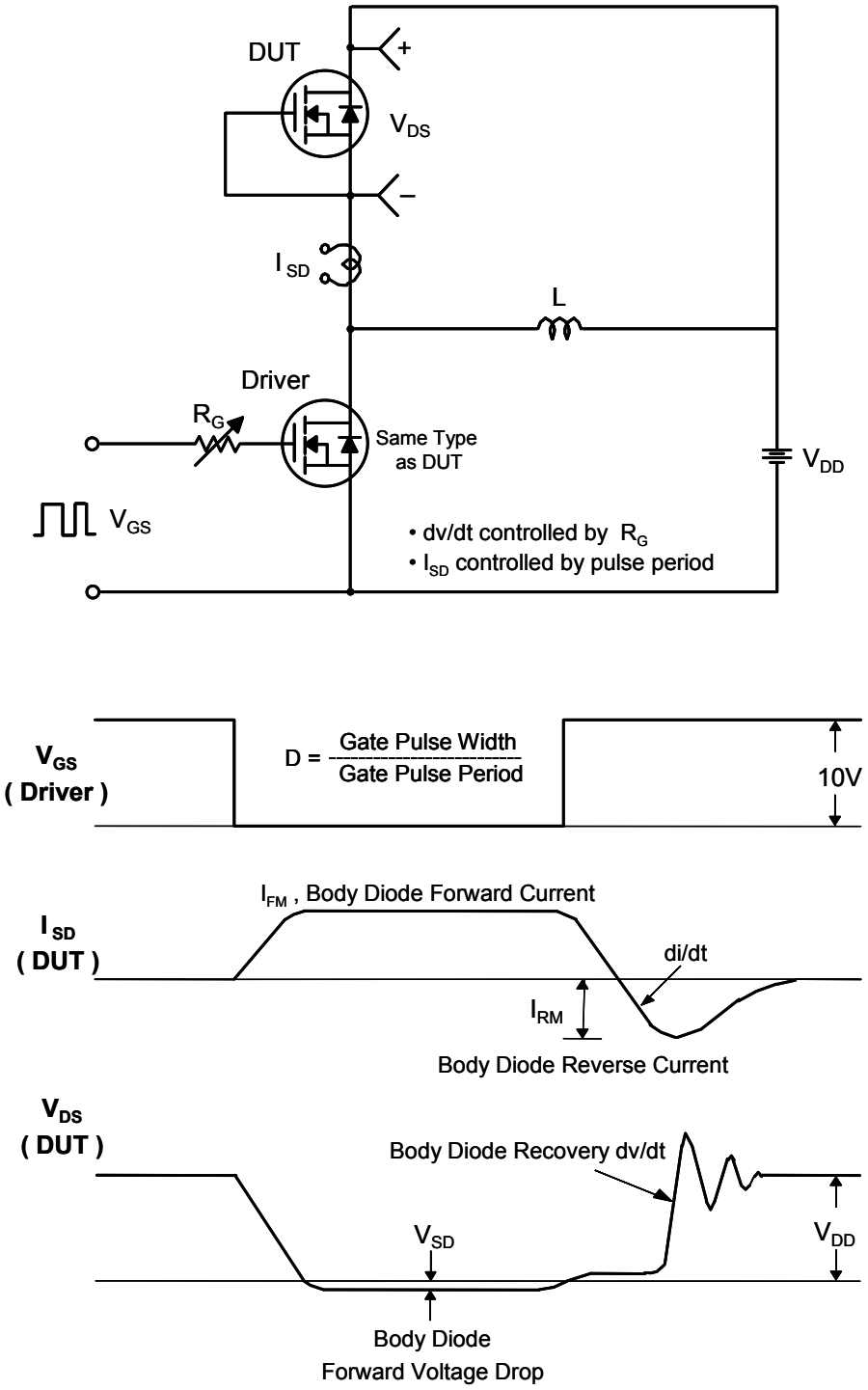
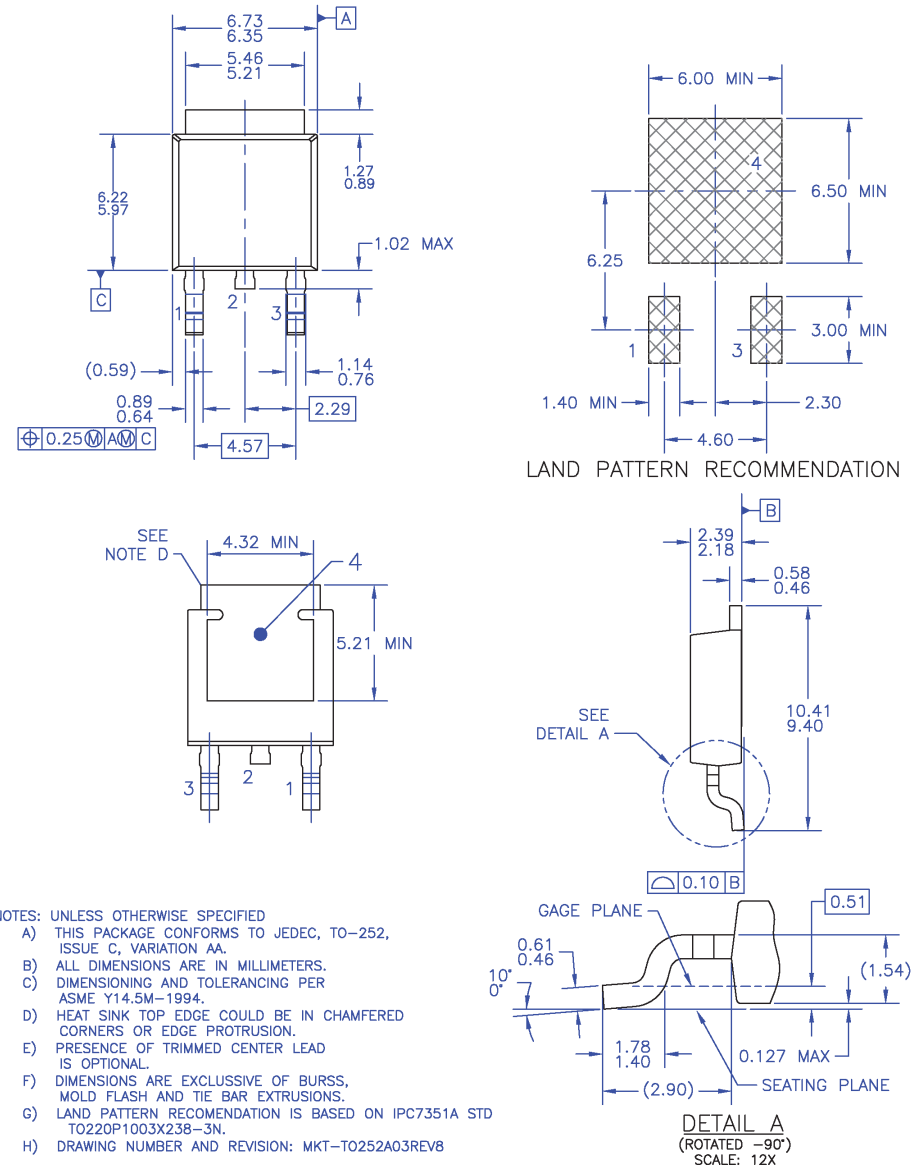


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

Mechanical Dimensions



NOTES: UNLESS OTHERWISE SPECIFIED

A) THIS PACKAGE CONFORMS TO JEDEC, TO−252, ISSUE C, VARIATION AA.
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M−1994.
D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.
E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL.
F) DIMENSIONS ARE EXCLUSSIVE OF BURSS, MOLD FLASH AND TIE BAR EXTRUSIONS.
G) LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD TO220P1003X238−3N.
H) DRAWING NUMBER AND REVISION: MKT−TO252A03REV8

Figure 16. TO252 (D-PAK), Molded, 3-Lead, Option AA&AB

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Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I66

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